

Notice of References Cited	Application/Control No. 10/527,526	Applicant(s)/Patent Under Reexamination SEKI ET AL.	
	Examiner Derek L. Dupuis	Art Unit 2883	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0048422 A1	04-2002	Cotteverte et al.	385/4
*	B	US-2003/0231689 A1	12-2003	Vurgaftman et al.	372/96
*	C	US-2002/0135863 A1	09-2002	Fukshima et al.	359/298
*	D	US-2002/0021878 A1	02-2002	Allan et al.	385/129
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 02/10843	02-2002	WO	Matsuura et al	G02F
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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